

Supplementary Information

Wallpapering-inspired spreading and wrinkling of atomically-thin materials

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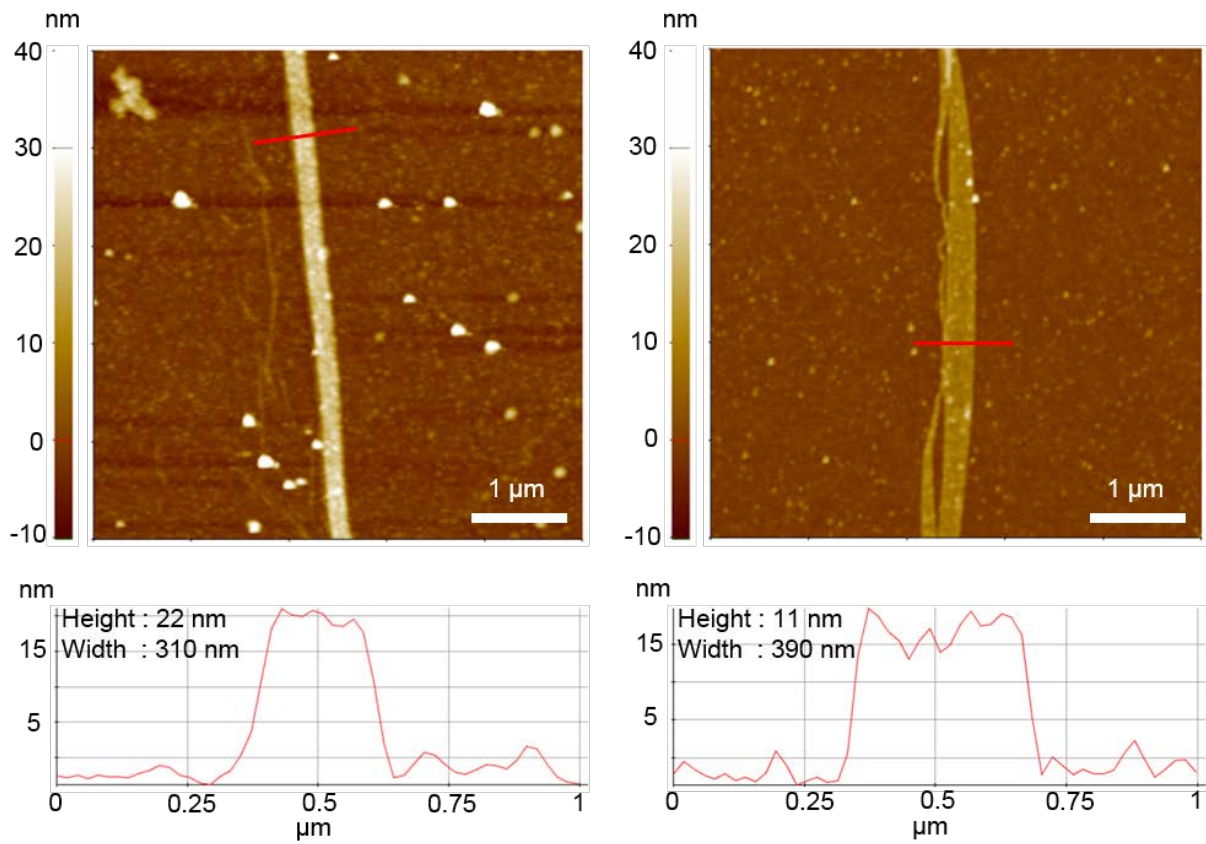


Fig. S1. AFM images and height-profiles of Gr wrinkles.

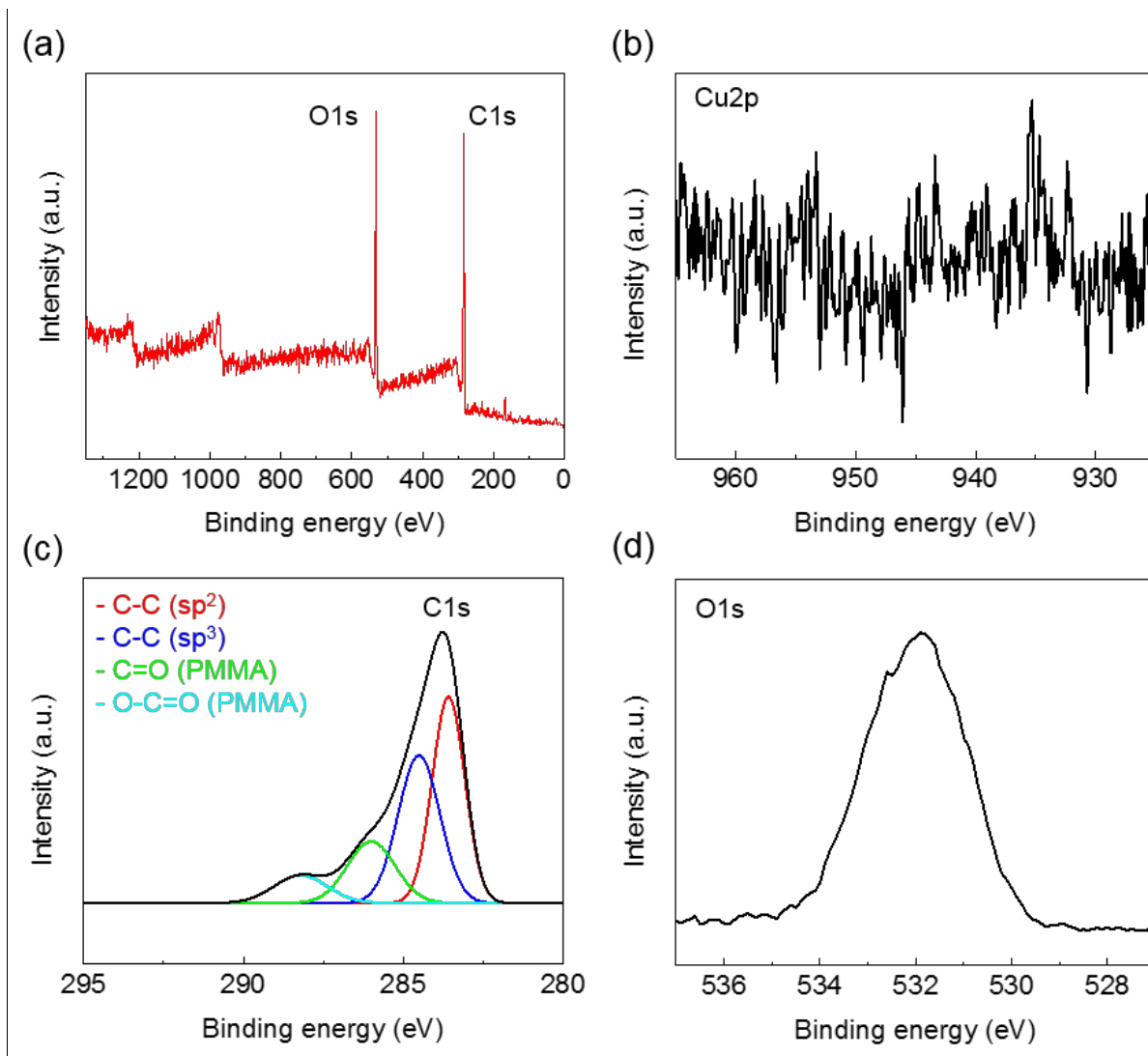


Fig. S2. XPS elemental analysis of Gr wrinkles on SiO₂ substrate.

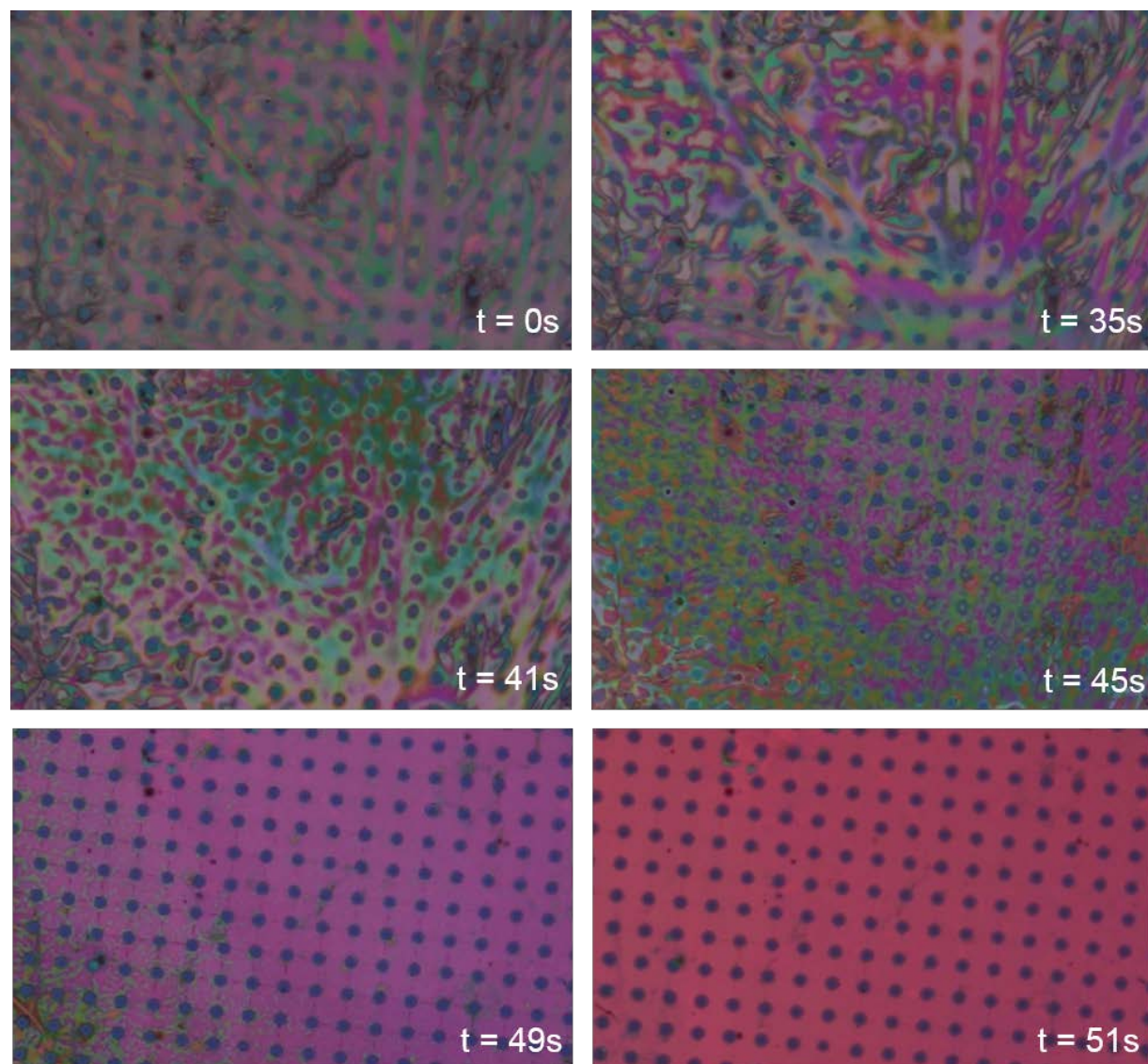


Fig. S3. In-situ OM images showing Gr/Cu ripple formation.

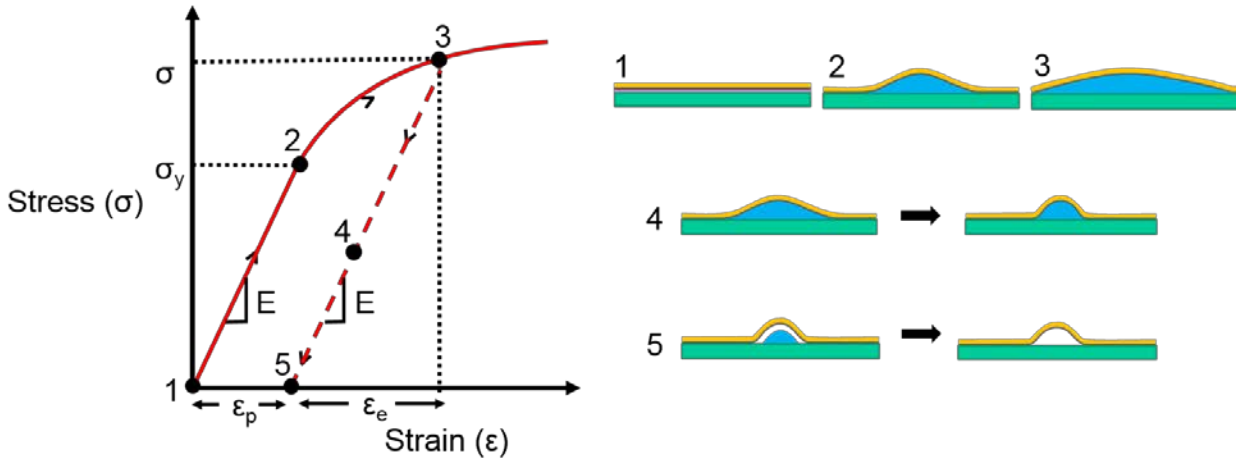


Fig. S4. Schematics of stress-strain behavior and corresponding geometries of Gr/Cu ripple formation steps.

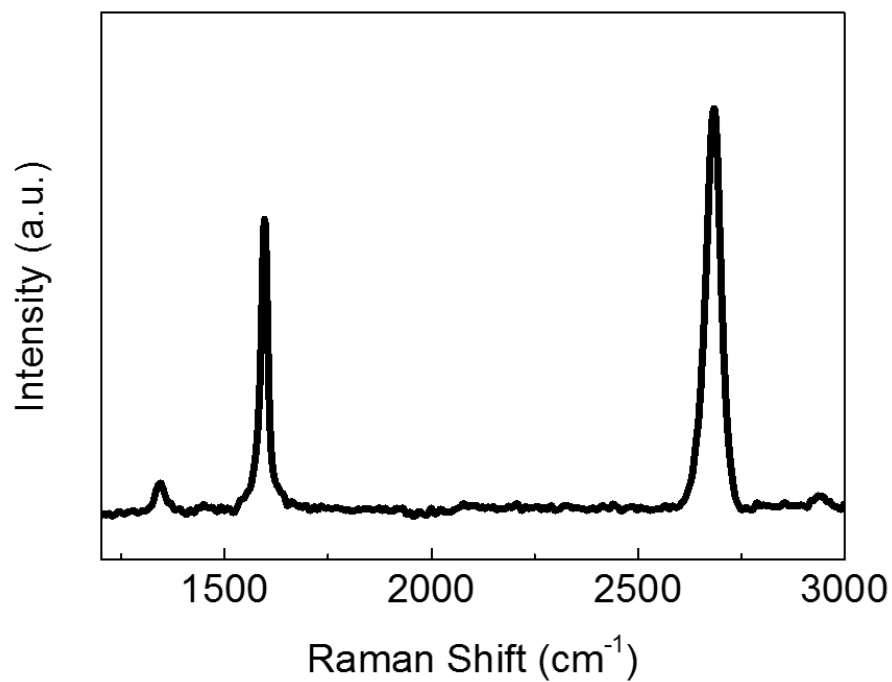


Fig. S5. Raman spectrum of CVD-grown graphene transferred onto SiO₂/Si substrate using conventional wet-transfer method.

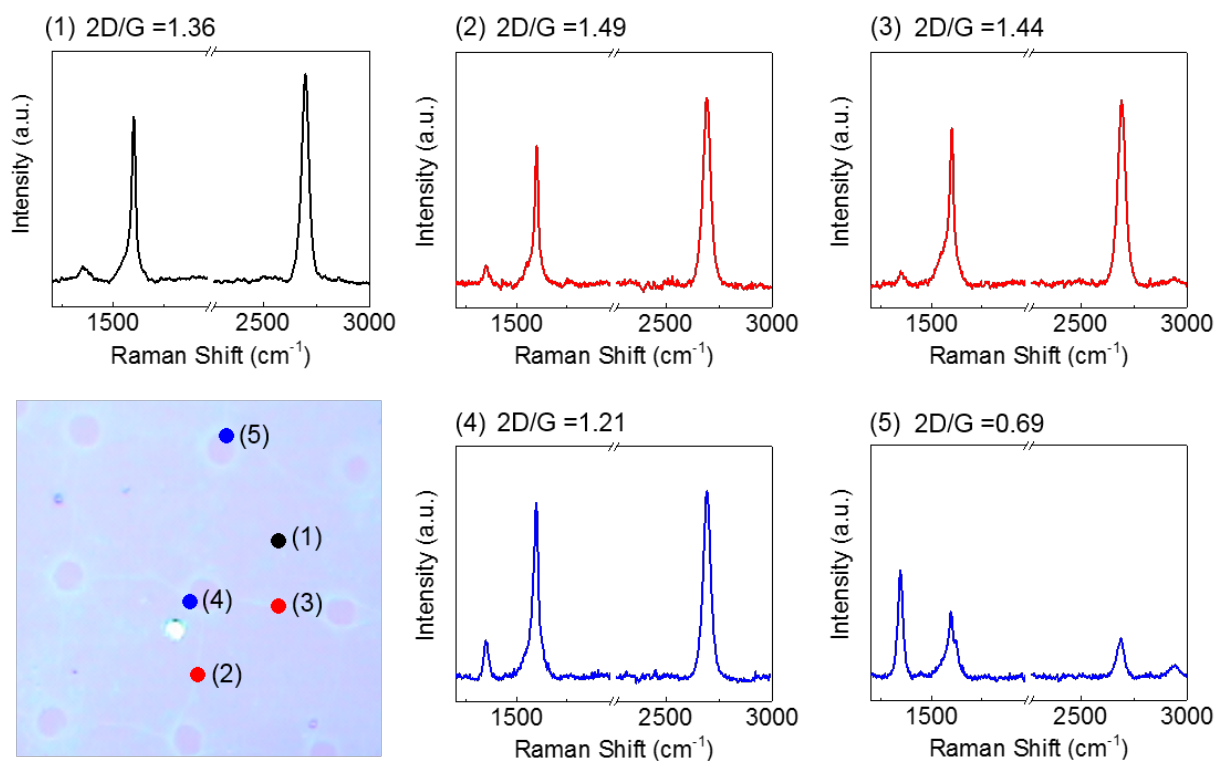


Fig. S6. Raman spectra from different positions.